

March 25<sup>th</sup>, 2026

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# Effects of Stabilizer Strength on the Delamination Resistance of REBCO Coated Conductors

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U.S. DEPARTMENT  
of **ENERGY**

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An aerial photograph of the Fermilab campus, featuring a prominent tall, curved tower and several large rectangular buildings. The image is overlaid with a dark blue color scheme. The number '01' is displayed in large white font on the left side, with a thin orange horizontal line underneath it.

01

# Motivation



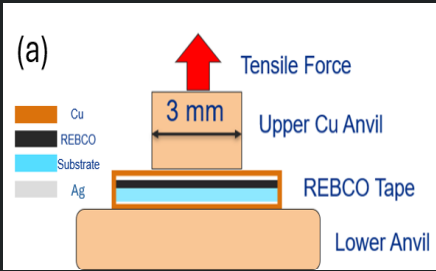


02

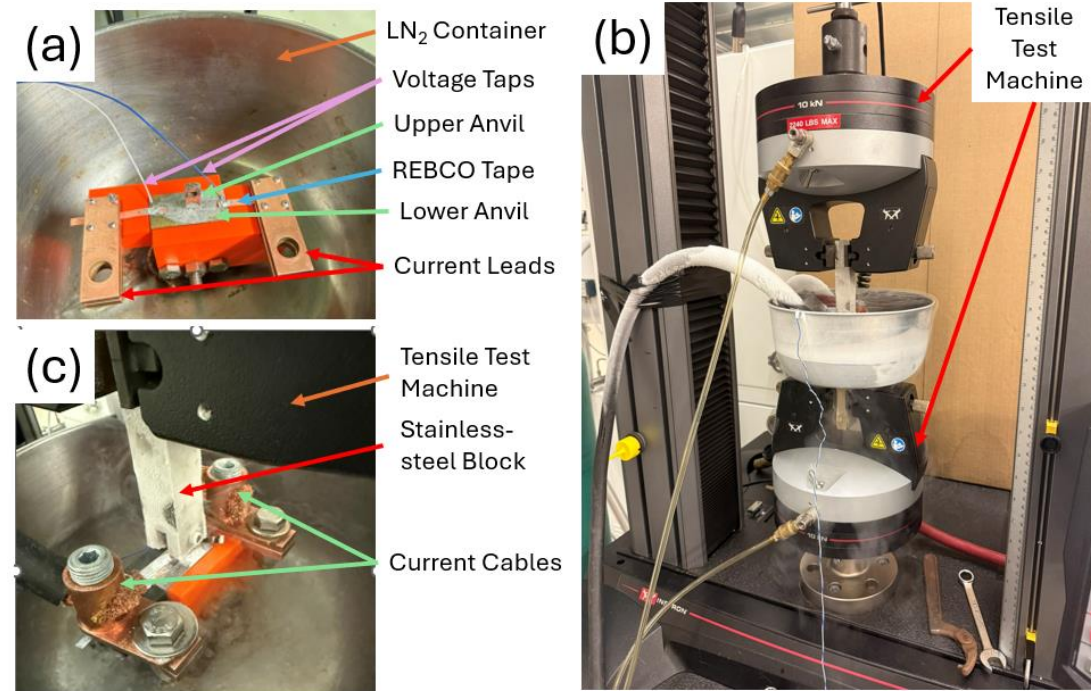
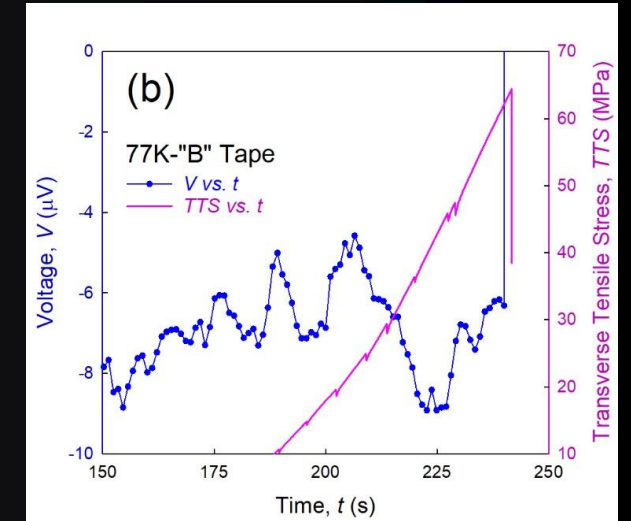
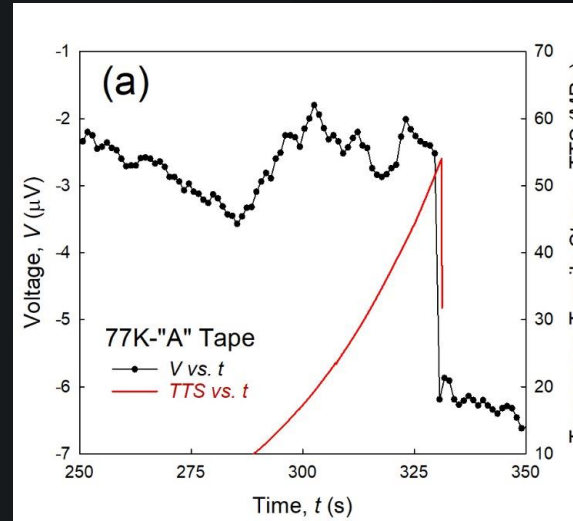
# Electromechanical Delamination Testing

# Electromechanical Delamination Testing

*Purpose: Build a relationship between  $I_c$  degradation and delamination strength for ReBCO tape.*



- Test critical current  $I_c$  without applied force at 77 K
- Input transport current equal to 99% of  $I_c$  at 77 K and maintain constant current
- Applied increasing tensile force at a constant displacement of 0.5 mm/min
- Test continues until mechanical delamination occurred



Parameter	"A"	"B"
$I_{c,77K}$	178	151
$I_{applied}/I_c$	0.983	0.987
Quench Time (s)	330.69	239.98
Delamination Time (s)	331.15	241.68
DS (MPa)	54.1	64.4

- Delamination and quench approximately occurred at the same time
- Prior to delamination,  $I_c$  degradation  $\leq 1.0\%$ .
- After delamination, REBCO tape was completely fractured, leading to the quench.

# 03

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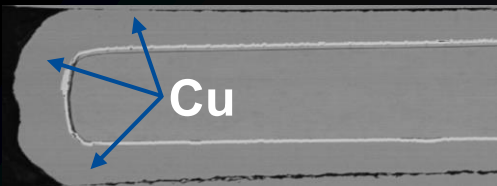
## Influence of Stabilizer Strength on Delamination Resistance



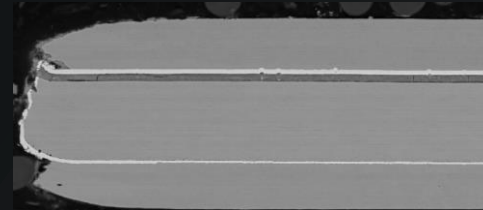
# Influence of Stabilizer Strength on Delamination Resistance

Hypothesis: *Enhancing delamination resistance by improving the mechanical strength of stabilizer*

Cu-electroplated ReBCO tape



DS of ReBCO=  
Stabilizer Contribution to  
Delamination Resistance  
+  
Interfacial bonding strength among  
multiple layers

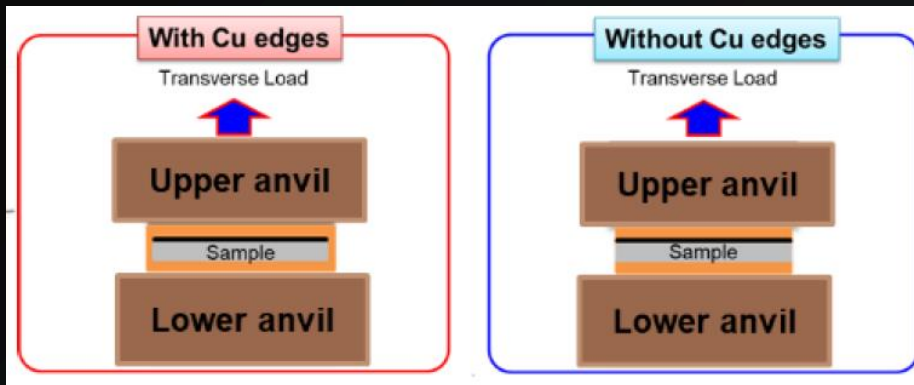


This study: Remove stabilizer edges by copper etching

Sample	“A”	“B”	“C”
Thickness of Stabilizer Edge (μm)	21.9 ± 0.2	18.6 ± 0.3	21.9 ± 0.1

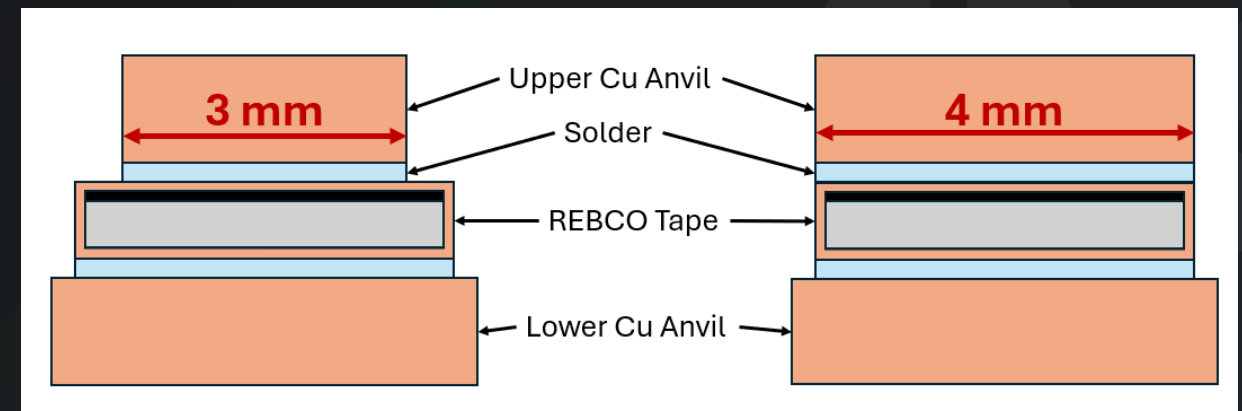
## Steps:

- Test *DS* (w.E.) and *DS* (n.E.) at RT
- Quantify the stabilizer contribution to delamination resistance  $\Delta DS = DS$  (w.E.) – *DS* (n.E.)
- Measure the mechanical strength of stabilizer edges



De Leon. M et al. *IEEE Trans. Supercond. Technol.*  
REBCO tape without edges (n.E.): The applied tensile load is only supported by the interlayer bonding

Delamination resistance contributed by stabilizer,  $\Delta DS$ :  
 $DS$  of REBCO with Cu edges – *DS* of REBCO without Cu edges  
 $DS$  (w.E.)                      *DS* (n.E.)

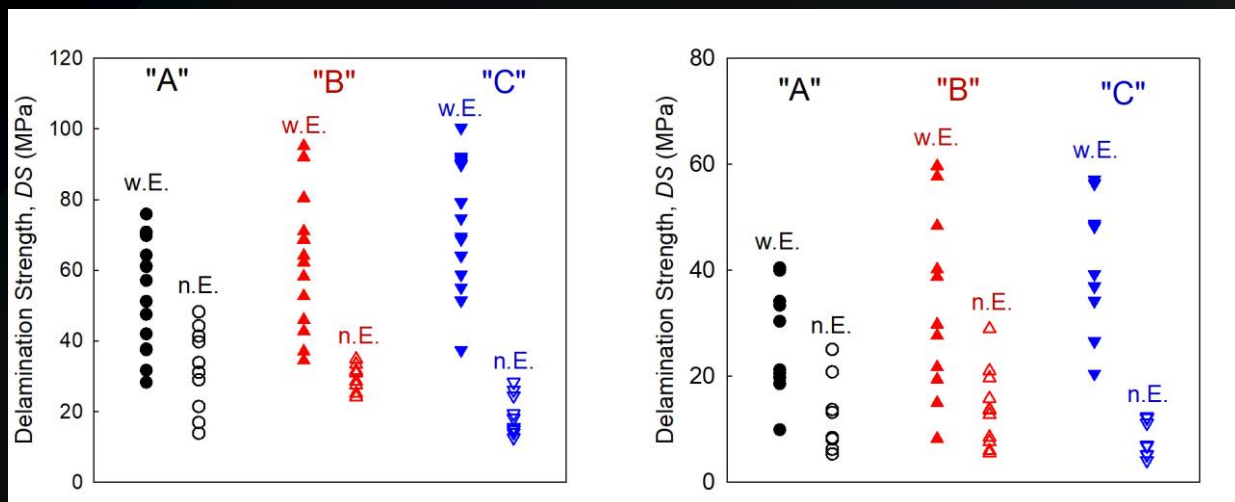




# Influence of Stabilizer Strength on Delamination Resistance

## 3-mm Anvil

## 4-mm Anvil



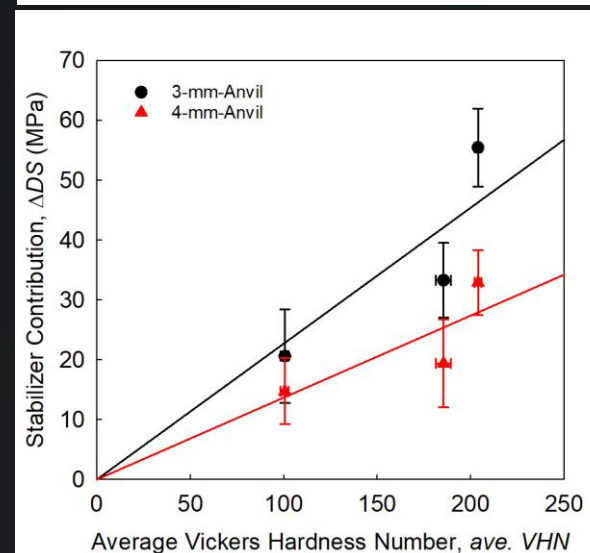
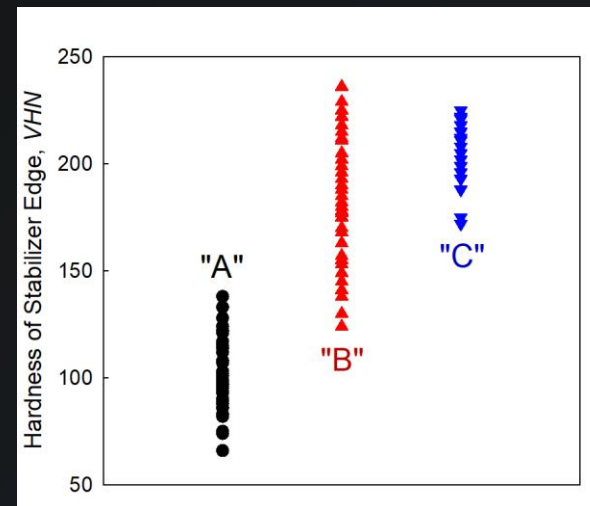
Sample	$\Delta DS$ , 3-mm-Anvil (MPa)	$\Delta DS$ , 4-mm-Anvil (MPa)
"A"	$20.6 \pm 7.8$	$14.7 \pm 5.5$
"B"	$33.3 \pm 6.3$	$19.4 \pm 7.3$
"C"	$55.5 \pm 7.8$	$32.9 \pm 5.4$

Vickers Hardness Number (VHN) = proxy of mechanical strengths of stabilizer

Copper alloys:

$$\text{Yield Strength (YS)} = 2.87 * \text{VHN}$$

$$\text{Ultimate Tensile Strength (UTS)} = 3.35 * \text{VHN}$$

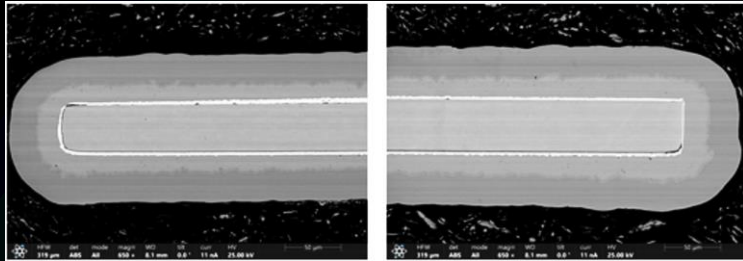


- HVN of "A" tapes is the lowest
- 90% of HVN values for "C" sample's stabilizer  $\geq 190$ , but 46% of HVN values for "B" sample's stabilizer  $\geq 190$ .
- Mean HVN of "C" is higher than that of "B".
- Delamination Resistance contributed from Stabilizer ( $\Delta DS$ ) versus Vickers Hardness Number (VHN) of Stabilizer Edge
- As VHN increases from 100 to 200,  $\Delta DS$  increase by 18 – 35 MPa at RT

# Influence of Stabilizer Strength on Delamination Resistance

Strategy to improve delamination resistance:

Deposit high-strength Ni-P layer onto REBCO tape



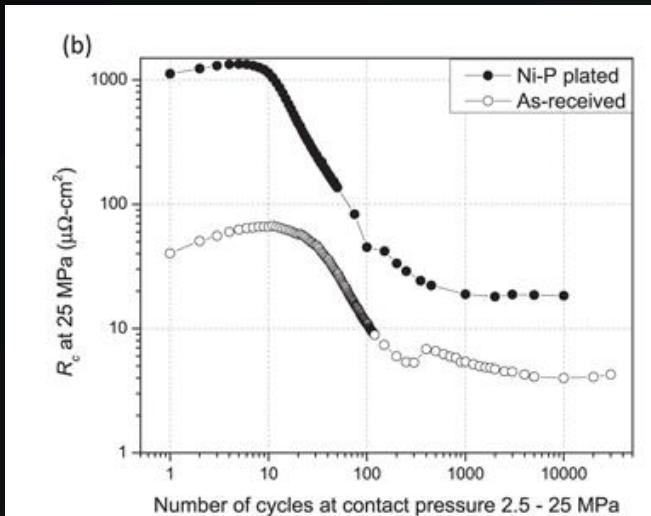
VHN:

- Ni-P: 300 – 600
- Cu: 100 – 200

## Another Advantage:

High Turn-to-Turn Resistivity,  $R_c$

- 20  $\mu\text{m}$  Ni – P plated layer  $\approx 14,000 \mu\Omega/\text{cm}^2$
- Suitable  $R_c = 1,000$  to  $100,000 \mu\Omega/\text{cm}^2$



## Drawback:

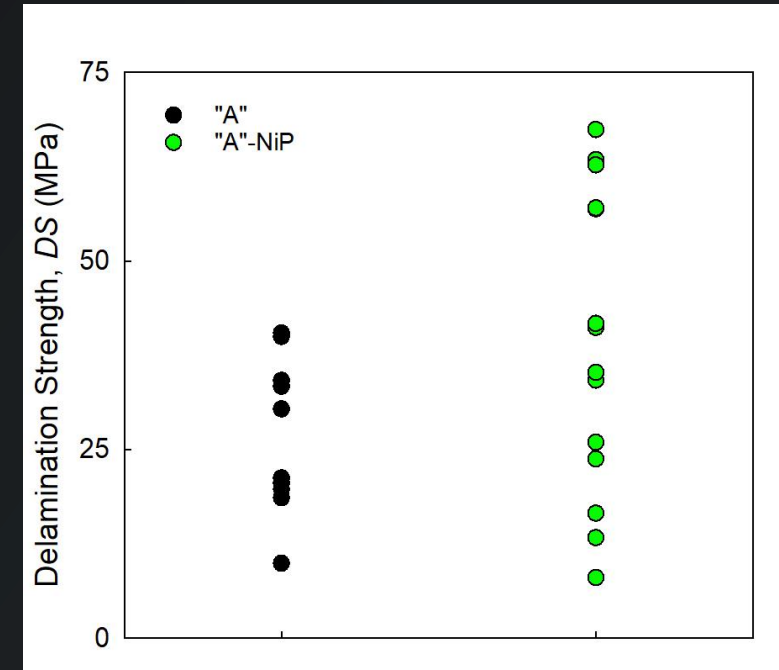
Sensitive to load cycling.

Jun Lu et al 2018 *Supercond. Sci. Technol.* **31** 085006

Linear Correlation:  $\Delta DS = 0.137 HVN$

- Mean HVN of Ni – P layer: 500
- Estimated  $\Delta DS$  (Ni-P) = 69 MPa

	Mean DS, (MPa)	Max. DS (MPa)
“A”	$26.8 \pm 3.2$	40.4
“A”-NiP	$39.3 \pm 5.0$	67.4
$\Delta DS$	$12.5 \pm 8.2$	27.0

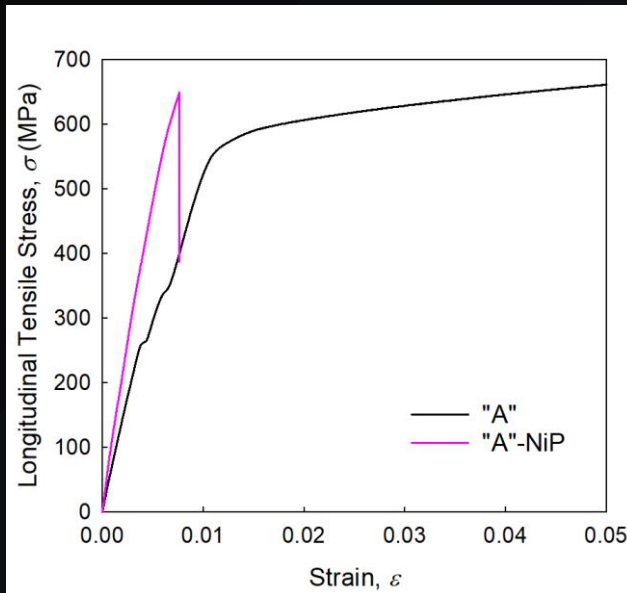




# Influence of Stabilizer Strength on Delamination Resistance

## Influence of Stabilizer Ductility:

Ni – P coating layer is brittle and highly susceptible to catastrophic, early failure under tensile loads



## If high-strength materials are used to replace Cu as the REBCO stabilizer:

it is essential to consider their toughness, i.e., the ability to combine high strength with sufficient ductility.

## Future Directions

Develop High-delamination-Resistance REBCO tape:

- Optimize the copper electroplating process to increase mechanical strengths of Cu stabilizer
  - Bath chemistry and temperature
  - Current density and mode (pulse)
  - Agitation condition
- Introduce high-strength materials into REBCO stabilizer.
  - Achieve a balance among mechanical strength, ductility, and resistivity.
- Increase interfacial bonding strength between REBCO layer and buffer stacks

# Summary and Acknowledgement

Build an electromechanical testing system to evaluate  $I_c$  degradation of REBCO tape under transverse tensile stress at 77 K.

Establish an effective strategy to enhance the delamination strength of REBCO tapes

I appreciate the technical support provided by my Fermilab colleagues (Daniele Turrioni, Steven Krave, and Maria Baldini).”



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